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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e300c3
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	133MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100Mbps (3)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	1.8V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	369-LFBGA
Supplier Device Package	369-PBGA (19x19)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8306svmabdca

  - Two TDM interfaces supporting up to 128 QUICC multichannel controller channels, each running at 64 kbps

For more information on QUICC Engine sub-modules, see *QUICC Engine Block Reference Manual with Protocol Interworking*.

- DDR SDRAM memory controller
  - Programmable timing supporting DDR2 SDRAM
  - Integrated SDRAM clock generation
  - 16-bit data interface, up to 266-MHz data rate
  - 14 address lines
  - The following SDRAM configurations are supported:
    - Up to two physical banks (chip selects), 256-Mbyte per chip select for 16 bit data interface.
    - 64-Mbit to 2-Gbit devices with x8/x16 data ports (no direct x4 support)
    - One 16-bit device or two 8-bit devices on a 16-bit bus,
  - Support for up to 16 simultaneous open pages for DDR2
  - One clock pair to support up to 4 DRAM devices
  - Supports auto refresh
  - On-the-fly power management using CKE
- Enhanced local bus controller (eLBC)
  - Multiplexed 26-bit address and 8-/16-bit data operating at up to 66 MHz
  - Eight chip selects supporting eight external slaves
    - Four chip selects dedicated
    - Four chip selects offered as multiplexed option
  - Supports boot from parallel NOR Flash and parallel NAND Flash
  - Supports programmable clock ratio dividers
  - Up to eight-beat burst transfers
  - 16- and 8-bit ports, separate $\overline{\text{LWE}}$ for each 8 bit
  - Three protocol engines available on a per chip select basis:
    - General-purpose chip select machine (GPCM)
    - Three user programmable machines (UPMs)
    - NAND Flash control machine (FCM)
  - Variable memory block sizes for FCM, GPCM, and UPM mode
  - Default boot ROM chip select with configurable bus width (8 or 16)
  - Provides two Write Enable signals to allow single byte write access to external 16-bit eLBC slave devices
- Integrated programmable interrupt controller (IPIC)
  - Functional and programming compatibility with the MPC8260 interrupt controller
  - Support for external and internal discrete interrupt sources
  - Programmable highest priority request

2.1.2 Power Supply Voltage Specification

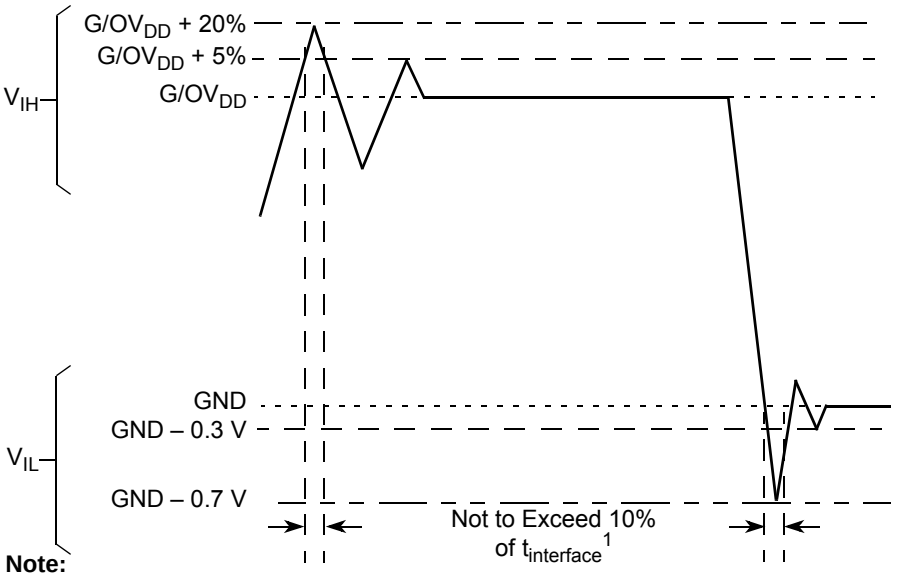
The following table provides the recommended operating conditions for the MPC8306S. Note that these values are the recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit	Note
Core supply voltage	V_{DD}	1.0 V ± 50 mV	V	1
PLL supply voltage	AV_{DD1} AV_{DD2} AV_{DD3}	1.0 V ± 50 mV	V	1
DDR2 DRAM I/O voltage	GV_{DD}	1.8 V ± 100 mV	V	1
Local bus, DUART, system control and power management, I^2C, SPI, MII, RMII, MII management, USB and JTAG I/O voltage	OV_{DD}	3.3 V ± 300 mV	V	1, 3
Junction temperature	T_A/T_J	0 to 105	°C	2

Notes:
1. GV_{DD}, OV_{DD}, AV_{DD}, and V_{DD} must track each other and must vary in the same direction—either in the positive or negative direction.
2. Minimum temperature is specified with T_A(Ambient Temperature); maximum temperature is specified with T_J(Junction Temperature).
3. OVDD here refers to NVDDA, NVDDB, NVDDC, NVDDF, NVDDG, and NVDDH from the ball map.

The following figure shows the undershoot and overshoot voltages at the interfaces of the MPC8306S



Note:
1. $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 2. Overshoot/Undershoot Voltage for GV_{DD}/OV_{DD}

Table 15. DDR2 SDRAM Input AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8V ± 100mV.

Parameter	Symbol	Min	Max	Unit	Note
266 MHz		–750	750		

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the equation: $t_{DISKEW} = \pm(T/4 - abs(t_{CISKEW}))$ where T is the clock period and $abs(t_{CISKEW})$ is the absolute value of t_{CISKEW}.

The following figure shows the input timing diagram for the DDR controller.

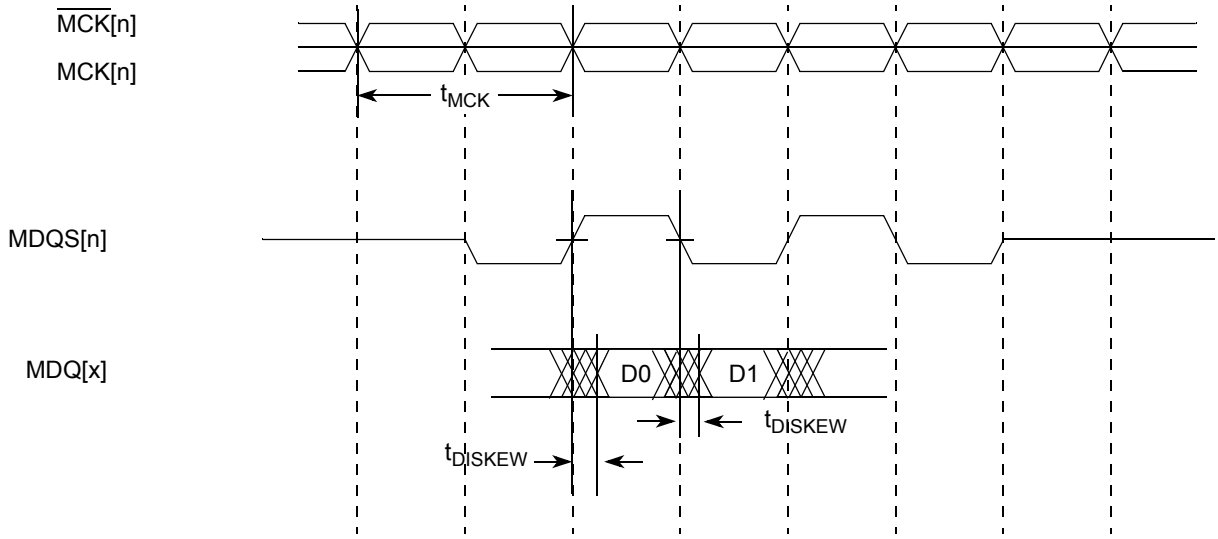


Figure 4. DDR Input Timing Diagram

6.2.2 DDR2 SDRAM Output AC Timing Specifications

The following table provides the output AC timing specifications for the DDR2 SDRAM interfaces.

Table 16. DDR2 SDRAM Output AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8V ± 100mV.

Parameter	Symbol[1]	Min	Max	Unit	Note
MCK cycle time, (MCK/$\overline{\text{MCK}}$ crossing)	t_{MCK}	5.988	8	ns	2
ADDR/CMD output setup with respect to MCK 266 MHz	t_{DDKHAS}	 2.5	 —	ns	3
ADDR/CMD output hold with respect to MCK 266 MHz	t_{DDKHAX}	 2.5	 —	ns	3
$\overline{\text{MCS}}$ output setup with respect to MCK 266 MHz	t_{DDKHCS}	 2.5	 —	ns	3

Table 16. DDR2 SDRAM Output AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8V ± 100mV.

Parameter	Symbol[1]	Min	Max	Unit	Note
$\overline{MCS}$ output hold with respect to MCK 266 MHz	t_{DDKHCX}	 2.5	 —	ns	3
MCK to MDQS Skew	t_{DDKHMH}	–0.6	0.6	ns	4
MDQ/MDM output setup with respect to MDQS 266 MHz	t_{DDKHDS}, t_{DDKLDS}	 0.9	 —	ns	5
MDQ/MDM output hold with respect to MDQS 266 MHz	t_{DDKHDX}, t_{DDKLDX}	 1100	 —	ps	5
MDQS preamble start	t_{DDKHMP}	0.75 x t_{MCK}	—	ns	6
MDQS epilogue end	t_{DDKHME}	0.4 x t_{MCK}	0.6 x t_{MCK}	ns	6

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{MCK}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{MCK}$, $\overline{MCS}$, and MDQ/MDM/MDQS. For the ADDR/CMD setup and hold specifications, it is assumed that the Clock Control register is set to adjust the memory clocks by 1/2 applied cycle.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK(n) clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. This is typically set to the same delay as the clock adjusts in the CLK_CNTL register. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. See the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.
6. t_{DDKHMP} follows the symbol conventions described in note 1.

The following figure provides the AC test load.

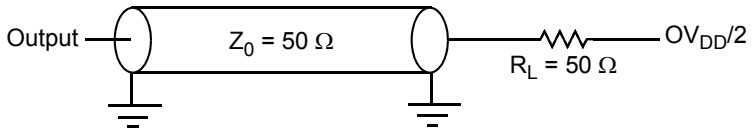


Figure 11. AC Test Load

The following figure shows the MII transmit AC timing diagram.

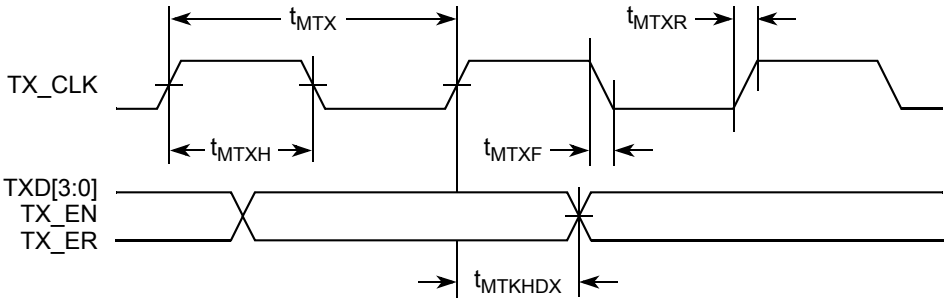


Figure 12. MII Transmit AC Timing Diagram

8.2.1.2 MII Receive AC Timing Specifications

The following table provides the MII receive AC timing specifications.

Table 21. MII Receive AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 300mV.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise V_{IL}(min) to V_{IH}(max)	t_{MRXR}	1.0	—	4.0	ns
RX_CLK clock fall time V_{IH}(max) to V_{IL}(min)	t_{MRXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Table 25. MII Management AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} is 3.3 V ± 300mV.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit	Note
MDC to MDIO delay	t_{MDKHDX}	10	—	70	ns	—
MDIO to MDC setup time	t_{MDDVKH}	8.5	—	—	ns	—
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	—
MDC fall time	t_{MDHF}	—	—	10	ns	—

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

The following figure shows the MII management AC timing diagram.

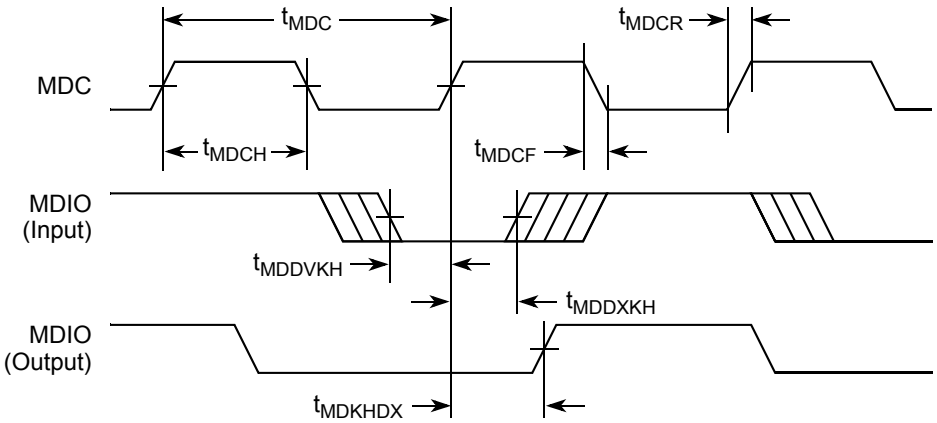


Figure 17. MII Management Interface Timing Diagram

Table 29. HDLC AC Timing Specifications[1] (continued)

Characteristic	Symbol[2]	Min	Max	Unit
Outputs—External clock high impedance	t_{HEKHOX}	1	8	ns
Inputs—Internal clock input setup time	t_{HIIVKH}	9	—	ns
Inputs—External clock input setup time	t_{HEIVKH}	4	—	ns
Inputs—Internal clock input hold time	t_{HIIXKH}	0	—	ns
Inputs—External clock input hold time	t_{HEIXKH}	1	—	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of QE_CLK_IN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{HIKHOX} symbolizes the outputs internal timing (HI) for the time t_{serial} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

The following figure provides the AC test load.

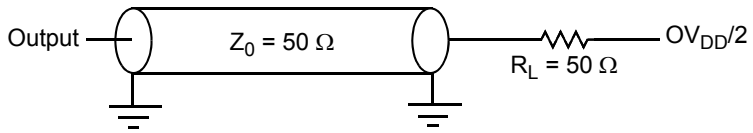
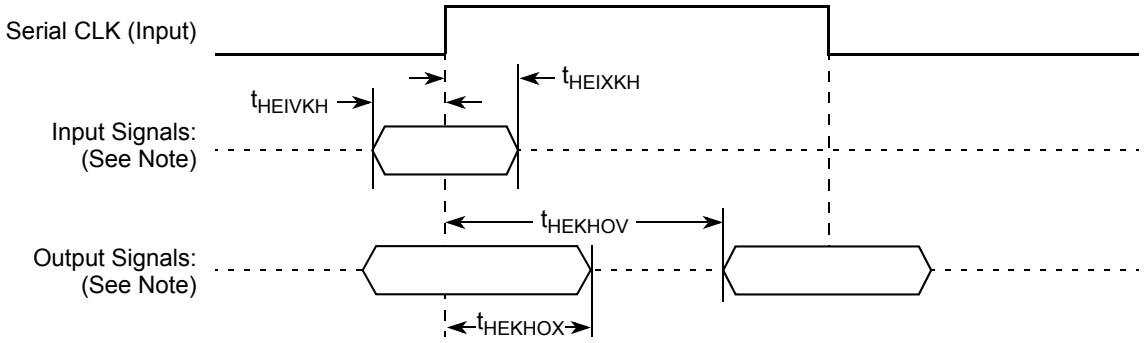


Figure 20. AC Test Load

Figure 21 and Figure 22 represent the AC timing from Table 29. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

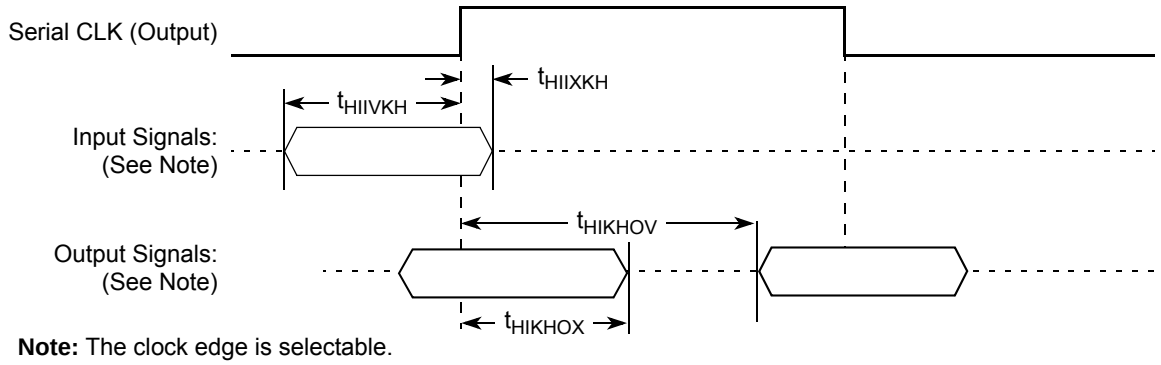
The following figure shows the timing with external clock.



Note: The clock edge is selectable.

Figure 21. AC Timing (External Clock) Diagram

The following figure shows the timing with internal clock.



Note: The clock edge is selectable.

Figure 22. AC Timing (Internal Clock) Diagram

11 USB

11.1 USB Controller

This section provides the AC and DC electrical specifications for the USB (ULPI) interface.

11.1.1 USB DC Electrical Characteristics

The following table provides the DC electrical characteristics for the USB interface.

Table 30. USB DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2.0	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
Input current	I_{IN}	—	±5	μA
High-level output voltage, I_{OH} = –100 μA	V_{OH}	OV_{DD} – 0.2	—	V
Low-level output voltage, I_{OL} = 100 μA	V_{OL}	—	0.2	V

11.1.2 USB AC Electrical Specifications

The following table describes the general timing parameters of the USB interface.

Table 31. USB General Timing Parameters

Parameter	Symbol[1]	Min	Max	Unit	Note
USB clock cycle time	t_{USCK}	15	—	ns	—
Input setup to USB clock—all inputs	t_{USIVKH}	4	—	ns	—
input hold to USB clock—all inputs	t_{USIXKH}	1	—	ns	—
USB clock to output valid—all outputs (except USBDR_STP_USBDR_STP)	t_{USKHOV}	—	7	ns	—

Table 31. USB General Timing Parameters (continued)

Parameter	Symbol[1]	Min	Max	Unit	Note
USB clock to output valid—USBDR_STP	t_{USKHOV}	—	7.5	ns	—
Output hold from USB clock—all outputs	t_{USKHOX}	2	—	ns	—

Note:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{USIXKH} symbolizes USB timing (USB) for the input (I) to go invalid (X) with respect to the time the USB clock reference (K) goes high (H). Also, t_{USKHOX} symbolizes us timing (USB) for the USB clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.

The following figures provide the AC test load and signals for the USB, respectively.

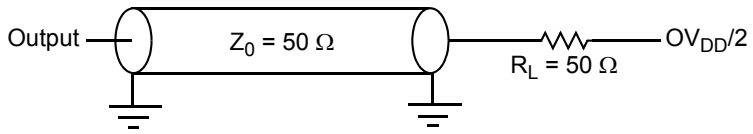


Figure 23. USB AC Test Load

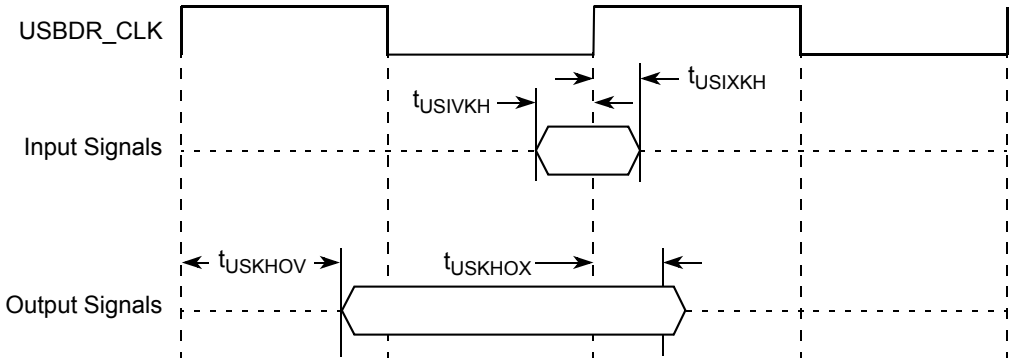


Figure 24. USB Signals

14 Timers

This section describes the DC and AC electrical specifications for the timers of the MPC8306S.

14.1 Timer DC Electrical Characteristics

The following table provides the DC electrical characteristics for the MPC8306S timer pins, including TIN, $\overline{\text{TOUT}}$, $\overline{\text{TGATE}}$, and RTC_PIT_CLK.

Table 36. Timer DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

14.2 Timer AC Timing Specifications

The following table provides the timer input and output AC timing specifications.

Table 37. Timer Input AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:
1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of SYS_CLK_IN. Timings are measured at the pin.
2. Timer inputs and outputs are asynchronous to any visible clock. Timer outputs should be synchronized before use by any external synchronous logic. Timer inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.

The following figure provides the AC test load for the timers.

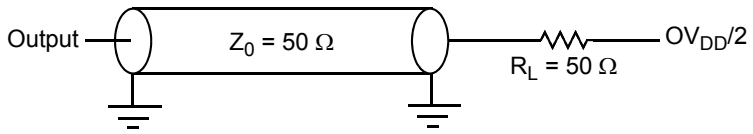


Figure 27. Timers AC Test Load

Table 42. SPI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

17.2 SPI AC Timing Specifications

The following table and provide the SPI input and output AC timing specifications.

Table 43. SPI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
SPI outputs—Master mode (internal clock) delay	t_{NIKHOV}	0.5	6	ns
SPI outputs—Slave mode (external clock) delay	t_{NEKHOV}	2	8	ns
SPI inputs—Master mode (internal clock) input setup time	t_{NIIVKH}	6	—	ns
SPI inputs—Master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns
SPI inputs—Slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns
SPI inputs—Slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of SPICLK to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).
3. All units of output delay must be enabled for 8306S output port spimosi (SPI Master Mode)
4. delay units must not be enabled for Slave Mode.

The following figure provides the AC test load for the SPI.

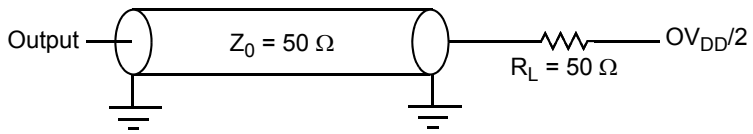


Figure 29. SPI AC Test Load

Figure 30 and Figure 31 represent the AC timing from Table 43. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

Table 44. JTAG Interface DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

18.2 JTAG AC Electrical Characteristics

This section describes the AC electrical specifications for the IEEE Std. 1149.1 (JTAG) interface of the MPC8306S. The following table provides the JTAG AC timing specifications as defined in Figure 33 through Figure 36.

Table 45. JTAG AC Timing Specifications (Independent of SYS_CLK_IN)[1]

At recommended operating conditions (see Table 2).

Parameter	Symbol[2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	11	—	ns	—
JTAG external clock rise and fall times	t_{JTGR}, t_{JTGF}	0	2	ns	—
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	3
Input setup times: Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 4	 — —	ns	4
Input hold times: Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 10 10	 — —	ns	4
Valid times: Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 2 2	 15 15	ns	5

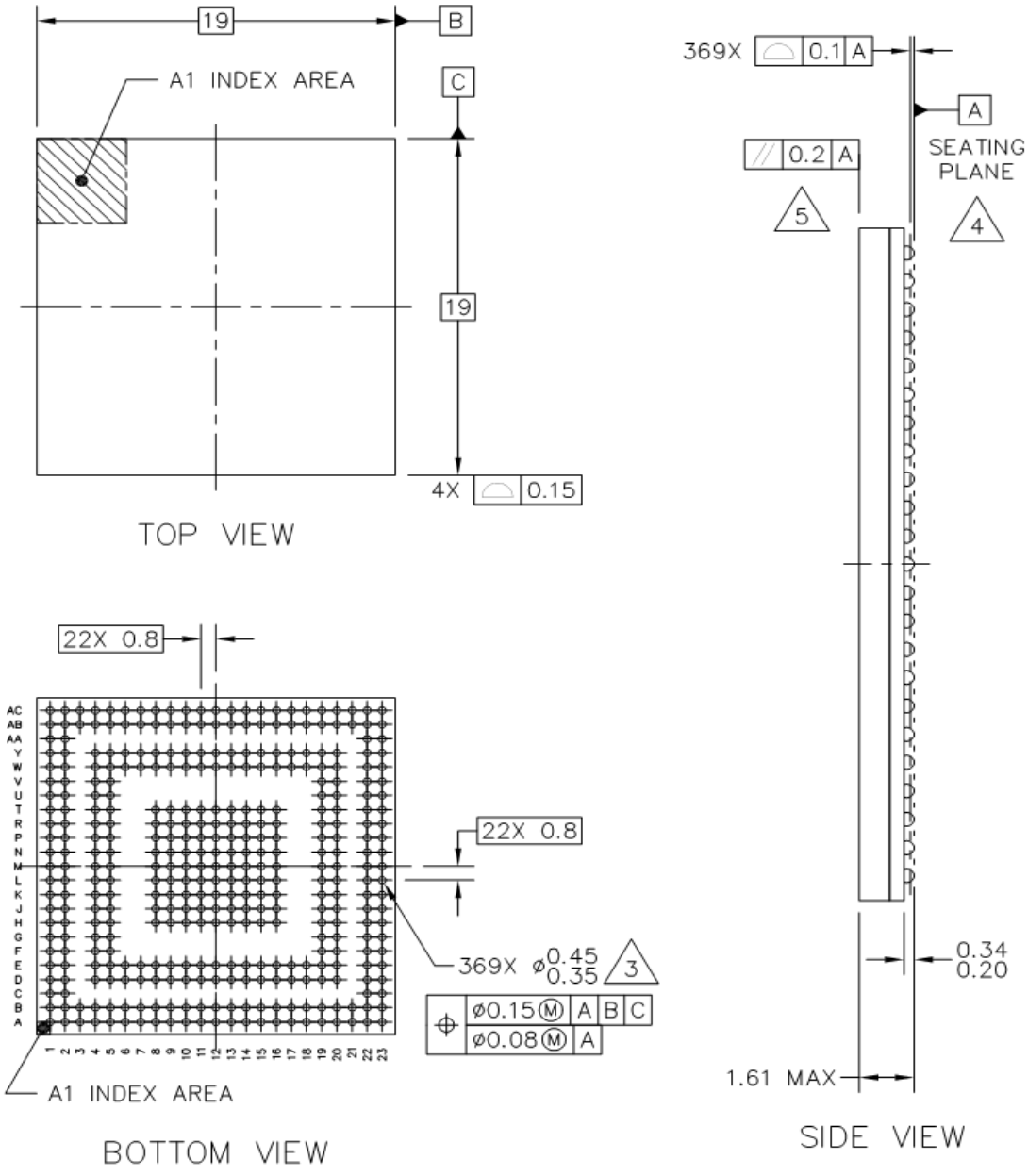


Figure 37. Mechanical Dimensions and Bottom Surface Nomenclature of the MPC8306S MAPBGA

Notes:
1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.

Table 46. MPC8306S Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LA[17]	B14	O	OV_{DD}	—
LA[18]	A14	O	OV_{DD}	—
LA[19]	A15	O	OV_{DD}	—
LA[20]	A16	O	OV_{DD}	—
LA[21]	B16	O	OV_{DD}	—
LA[22]	A17	O	OV_{DD}	—
LA[23]	B17	O	OV_{DD}	—
LA[24]	A18	O	OV_{DD}	—
LA[25]	B19	O	OV_{DD}	—
LCS_B[0]	A19	O	OV_{DD}	3
LCS_B[1]	B20	O	OV_{DD}	3
LCS_B[2]	A20	O	OV_{DD}	3
LCS_B[3]	A21	O	OV_{DD}	3
LCLK[0]	D13	O	OV_{DD}	—
LGPL[0]	B22	O	OV_{DD}	—
LGPL[1]	D16	O	OV_{DD}	—
LGPL[2]	D19	O	OV_{DD}	—
LGPL[3]	D17	O	OV_{DD}	—
LGPL[4]	E18	IO	OV_{DD}	—
LGPL[5]	E19	O	OV_{DD}	—
LWE_B[0]	D15	O	OV_{DD}	—
LWE_B[1]	D14	O	OV_{DD}	—
LBCTL	A22	O	OV_{DD}	—
LALE	B23	O	OV_{DD}	—
JTAG				
TCK	A3	I	OV_{DD}	—
TDI	B5	I	OV_{DD}	3
TDO	D7	O	OV_{DD}	—
TMS	A4	I	OV_{DD}	3
TRST_B	D8	I	OV_{DD}	3
Test Interface				
TEST_MODE	A5	I	OV_{DD}	—
System Control Signals				
HRESET_B	U20	IO	OV_{DD}	1
PORESET_B	V20	I	OV_{DD}	—

Table 46. MPC8306S Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Clock Interface				
QE_CLK_IN	P23	I	OV_{DD}	—
SYS_CLK_IN	R23	I	OV_{DD}	—
RTC_PIT_CLOCK	V23	I	OV_{DD}	—
Miscellaneous Signals				
QUIESCE_B	A2	O	OV_{DD}	—
THERM0	D6	I	OV_{DD}	—
GPIO				
GPIO[0]/MSRCID0 (DDR ID)	E5	IO	OV_{DD}	—
GPIO[1]/MSRCID1 (DDR ID)	E6	IO	OV_{DD}	—
GPIO[2]/MSRCID2 (DDR ID)	D4	IO	OV_{DD}	—
GPIO[3]/MSRCID3 (DDR ID)	C2	IO	OV_{DD}	—
GPIO[4]/MSRCID4 (DDR ID)	C1	IO	OV_{DD}	—
GPIO[5]/MDVAL (DDR ID)	B1	IO	OV_{DD}	—
GPIO[6]/QE_EXT_REQ_3	B3	IO	OV_{DD}	—
GPIO[7]/QE_EXT_REQ_1	B2	IO	OV_{DD}	—
USB				
USBDR_PWRFAULT/IIC_SDA2/CE_PIO_1	AC4	IO	OV_{DD}	2
USBDR_CLK/UART2_SIN[2]/UART2_CTS_B[1]	Y9	I	OV_{DD}	
USBDR_DIR/IIC_SCL2	AC3	IO	OV_{DD}	2
USBDR_NXT/UART2_SIN[1]/QE_EXT_REQ_4	AC2	IO	OV_{DD}	—
USBDR_PCTL[0]/UART2_SOUT[1]/ LB_POR_CFG_BOOT_ECC	AB3	IO	OV_{DD}	—
USBDR_PCTL[1]/UART2_SOUT[2]/ UART2_RTS_B1/LB_POR_BOOT_ERR	Y8	O	OV_{DD}	—
USBDR_STP/QE_EXT_REQ_2	W6	IO	OV_{DD}	—
USBDR_TXDRXD[0]/UART1_SOUT[1]/ GPIO[32]/QE_TRB_O	AB7	IO	OV_{DD}	—
USBDR_TXDRXD[1]/UART1_SIN[1]/GPIO[33]/ QE_TRB_I	AB8	IO	OV_{DD}	—
USBDR_TXDRXD[2]/UART1_SOUT[2]/ UART1_RTS_B1/QE_BRG[1]	AC6	IO	OV_{DD}	—
USBDR_TXDRXD[3]/UART1_SIN[2]/ UART1_CTS_B1/QE_BRG[2]	AC5	IO	OV_{DD}	—
USBDR_TXDRXD[4]/GPIO[34]/QE_BRG[3]	AB5	IO	OV_{DD}	—
USBDR_TXDRXD[5]/GPIO[35]/QE_BRG[4]	Y7	IO	OV_{DD}	—
USBDR_TXDRXD[6]/GPIO[36]/QE_BRG[9]	Y6	IO	OV_{DD}	—

Table 46. MPC8306S Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
V_{DD}	H8,H9,H10,H11,H12,H13,H14,H15,H16,J8,J16,K8,K16,M8,N16,P8,P16,R8,R16,T8,T9,T10,T11,T12,T13,T14,T15,T16	—	—	—
VSS	A1,B4,B6,B9,B12,B15,B18,B21,C22,D2,D5,D18,D20,F2,F22,J2,J9,J10,J11,J12,J13,J14,J15,J22,K4,K9,K10,K11,K12,K13,K14,K15,L9,L10,L11,L12,L13,L14,L15,M2,M9,M10,M11,M12,M13,M14,M15,M22,N9,N10,N11,N12,N13,N14,N15,P9,P10,P11,P12,P13,P14,P15,R2,R9,R10,R11,R12,R13,R14,R15,R22,T4,V2,V19,V22,W4,Y19,AA2,AA22,AB4,AB6,AB9,AB12,AB15,AB18,AB21,AC1,AC23	—	—	—
NC	A23	—	—	—

Notes
1. This pin is an open drain signal. A weak pull-up resistor (1 kΩ) should be placed on this pin to OV_{DD}
2. This pin is an open drain signal. A weak pull-up resistor (2-10 kΩ) should be placed on this pin to OV_{DD}
3. This pin has weak pull-up that is always enabled.

Table 54. Suggested PLL Configurations

Conf No.	SPMF	Core PLL	CEPMF	CEDF	Input Clock Frequency (MHz)	CSB Frequency (MHz)	Core Frequency (MHz)	QUICC Engine Frequency (MHz)
1	0100	0000100	0111	0	33.33	133.33	266.66	233
2	0010	0000100	0111	1	66.67	133.33	266.66	233
3	0100	0000101	0111	0	33.33	133.33	333.33	233
4	0101	0000101	1001	0	25	125	312.5	225
5	0010	0000101	0111	1	66.67	133.33	333.33	233

T_T = thermocouple temperature on top of package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

21.1.5 Heat Sinks and Junction-to-Case Thermal Resistance

In some application environments, a heat sink is required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction-to-case thermal resistance and a case to ambient thermal resistance as shown in the following equation:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA} \qquad \textit{Eqn. 4}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, air flow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

Accurate thermal design requires thermal modeling of the application environment using computational fluid dynamics software which can model both the conduction cooling and the convection cooling of the air moving through the application. Simplified thermal models of the packages can be assembled using the junction-to-case and junction-to-board thermal resistances listed in the thermal resistance table. More detailed thermal models can be made available on request.

21.2 Heat Sink Attachment

When attaching heat sinks to these devices, an interface material is required. The best method is to use thermal grease and a spring clip. The spring clip should connect to the printed-circuit board, either to the board itself, to hooks soldered to the board, or to a plastic stiffener. Avoid attachment forces which would lift the edge of the package or peel the package from the board. Such peeling forces reduce the solder joint

Table 57. Part Numbering Nomenclature

MPC	*nnnn*	*C*	*VM*	*AF*	*D*	*C*	*A*
Product Code	**Part Identifier**	**Temperature Range[1]**	**Package[2]**	**e300 Core Frequency[3]**	**DDR2 Frequency**	**QUICC Engine Frequency**	**Revision Level**
MPC	8306S	Blank = 0 to 105°C C = –40 to 105°C	VM = Pb-free	AB = 133MHz AC = 200 MHz AD = 266 MHz AF = 333 MHz	D = 266 MHz F = 333 MHz	C = 233 MHz	Contact local Freescale sales office

Notes:
1. Contact local Freescale office on availability of parts with C temperature range.
2. See Section 19, “Package and Pin Listings,” for more information on available package types.
3. Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by Part Number Specifications may support other maximum core frequencies.

23.2 Part Marking

Parts are marked as in the example shown in the following figure.

MAPBGA

Notes:
ATWLYYWW is the traceability code.
CCCCC is the country code.
MMMMM is the mask number.
YWWLAZ is the assembly traceability code.

Figure 43. Freescale Part Marking for MAPBGA Devices

The following table shows the SVR Settings.

Table 58. SVR Settings

Device	Package	SVR (Rev 1.0)	SVR (Rev 1.1)
MPC8306S	MAPBGA	0x8110_0210	0x8110_0211
Note: PVR = 0x8085_0020			

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